

Trash

USPAT-US POPUL ERO; IPO; DERWENT, IBM, TOB

Default operator:
☒ Plural

☒ Highlight all hit terms initially

	U	I	Document ID	Issue Date	Pages	Title	Current OR	Current XR	Retrieval	Inventor	S	C	P	2	3	4
6	<input type="checkbox"/>	<input type="checkbox"/>	US 6621710	20030916	8	Modular probe card assembly	361/774	324/754; 324/762;		Cheng, Shih-Jye et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input type="checkbox"/>
7	<input type="checkbox"/>	<input type="checkbox"/>	US 6600335	20030729	22	Method for ball grid array chip packages having integrated compliant probe for wafer level test	324/765	257/E25.02 31.		Tay, Wu Yean et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
8	<input type="checkbox"/>	<input type="checkbox"/>	US 6528984	20030304	23	Integrated compliant probe for wafer level test	324/158.1	324/754; 439/66;		Beaman, Brian Samuel et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
9	<input type="checkbox"/>	<input type="checkbox"/>	US 6480012	20021112	21	Probe card device	324/754	324/158.1; 324/758		Komori, Junko	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
10	<input type="checkbox"/>	<input type="checkbox"/>	US 6064215	20000516	15	High temperature probe card for testing integrated probe assembly and method for switchable method for card for maintaining the position of testing semiconductor devices	324/754	324/762		Kister, January	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
11	<input type="checkbox"/>	<input type="checkbox"/>	US 5923178	19990713	20	Probe assembly and method for switchable method for card for maintaining the position of testing semiconductor devices	324/754	324/757; 324/762		Higgins, H. Dan et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input type="checkbox"/>
12	<input type="checkbox"/>	<input type="checkbox"/>	US 5670889	19970923	18	Probe card for maintaining the position of testing semiconductor devices	324/760	324/761; 324/762		Okubo, Masao et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
13	<input type="checkbox"/>	<input type="checkbox"/>	US 6127837	20001003	19	Method of testing semiconductor devices	324/765	324/754; 324/757		Yamamoto, Shiohisa et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>